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Metaverse and Digital Twins

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Message from the Guest Editors

The rapid advancement of VR/AR and digital twins technology in recent years has enabled the spread of their innovative application in science, engineering, the humanities and art, as well as culture and heritage, etc. VR/AR and digital twins are often used for data processing. Visualizing, analyzing, and manipulating such big and complex data in VR/AR and digital twins are thus challenging. It is important to discuss and share the outcomes of fundamental research, novel use cases and applications including algorithms, methodologies and techniques involving VR/AR and digital twins. The design and development of VR/AR and digital twins systems for various types of applications are increasingly desired, with a highly interdisciplinary nature. For this Special Issue, prospective authors are invited to submit their research findings on state-of-the-art reviews, novel ideas, theoretical frameworks, practical analysis, and innovative applications of VR/AR and digital twins in relevant fields. It aims to stimulate future interdisciplinary research and the development of VR/AR and digital twins.











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Message from the Editor-in-Chief

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